

Notice of References Cited

Application/Control No.

10/052,411

Applicant(s)/Patent Under
Reexamination
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Examiner

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Art Unit

2611

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,088,404	07-2000	Jekal, Heon	375/341
	B	US-			
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